Appl. No. 10/637,224 Amdt. Dated November 30, 2004 Reply to Office Action of August 31, 2004

## Amendments to the Specification

On page 4, in the "Brief Description of the Drawings" section, following the description of Fig. 9 (following line 17), add the following new paragraph:

Fig. 10 is a flow diagram illustrating a method for examining a signal supply apparatus according to the present invention.

Replace the paragraph beginning at page 5, line 30, and ending at page 6, line 5, with the following amended paragraph:

In an examination mode  $\underline{200}$  in accordance with the present embodiment, and with reference to the flow diagram of Fig. 10, the output lines 16-1 through 16-3 of the respective three voltage followers 14-1 through 14-3 are short-circuited (step  $\underline{202}$ ). Then, in step 204, a current value of the closed circuit thus short-circuited is measured through the output examination terminals 32 and 34. For example, the current value is measured as  $I_1$ . In this instance, when the measured composite current value  $I_1$  is less than a reference current value  $I_{refl}$  (steps 206, 208), the apparatus is determined to be a good product (step 210). Conversely, when the composite current value  $I_1$  exceeds the reference current value  $I_{refl}$ , the apparatus is determined to be a bad product (step 212).